

INTERNATIONAL STANDARD

NORME INTERNATIONALE

**Connectors for electronic equipment – Tests and measurements –
Part 26-100: Measurement setup, test and reference arrangements and
measurements for connectors according to IEC 60603-7 – Tests 26a to 26g**

**Connecteurs pour équipements électroniques – Essais et mesures –
Partie 26-100: Montage de mesure, dispositifs d'essai et de référence et mesures
pour les connecteurs conformes à la CEI 60603-7 – Essais 26a à 26g**



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INTERNATIONAL ELECTROTECHNICAL COMMISSION

CONNECTORS FOR ELECTRONIC EQUIPMENT – TESTS AND MEASUREMENTS –

Part 26-100: Measurement setup, test and reference arrangements and measurements for connectors according to IEC 60603-7 – Tests 26a to 26g

FOREWORD

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International Standard IEC 60512-26-100 has been prepared by subcommittee 48B: Connectors, of IEC technical committee 48: Electromechanical components and mechanical structures for electronic equipment.

This standard cancels and replaces the Annexes of IEC 60603-7-x documents dealing with transmission characteristics for interoperability and backward compatibility.

This standard is to be read in conjunction with IEC 60512-1 and IEC 60512-1-100 which explains the structure of the IEC 60512 series.

The text of this standard is based on the following documents:

FDIS	Report on voting
48B/1892/FDIS	48B/1925/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts of the IEC 60512 series, under the general title *Connectors for electronic equipment – Tests and measurements*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

INTRODUCTION

Detail specifications for 8-way, free and fixed connectors such as IEC 60603-7-4:2005 and IEC 60603-7-5:2007 define measurement setup, test and reference arrangements and measurements for interoperability and backward compatibility tests for connectors according IEC 60603-7 up to 250 MHz for insertion loss (IL), near end crosstalk (NEXT), far end crosstalk (FEXT), return loss (RL) and balance (transverse conversion loss, TCL, and transverse conversion transfer loss, TCTL) as well as the de-embedding method to qualify the fixed (outlet) connector.

This standard keeps the technical content of the test methods specified in the annexes C to J as specified in IEC 60603-7-4:2005 and annexes C to K as specified in IEC 60603-7-5:2007, but it structures and harmonizes the measurements for better readability. This standard is intended to be referenced by the future second editions of IEC 60603-7-x and the future first editions of IEC 60603-7-xy (under preparation). This standard is intended to be referenced by IEC 60603-7-x Edition 2.0 and IEC 60603-7-xy Edition 1.0 standards (under preparation) and may be referenced for all IEC standards with 60603-7 interface.

IEC 60516-26-100: Connectors for electronic equipment – Tests and measurements – Part 26-100, consists of the following clauses:

- Clause 3: General requirements for measurement setup
- Clause 4: Connector measurement up to 250 MHz

NOTE 1 Clauses 3 and 4 define the measurement procedures to qualify the outlet

- Clause 5: Construction and qualification of test plugs

NOTE 2 The wiring of the plug has an effect on the mated connector performance. Extensive measurements show that NEXT and FEXT are affected in a particular way so that the properties of the test plug must be controlled. To ensure adequate performance for the outlet over the expected range of different plug wiring, it shall be tested with a set of up to 12 test plugs with different NEXT performances. The outlet complies with the NEXT requirements of the standard only if all the combinations comply with their requirements for near end crosstalk. FEXT is handled in a similar way, but only one test plug is required. Clause 5 describes the construction and qualification of test plugs. Test plugs are used in the laboratory as long as possible to avoid the costly procedure to find new test plugs.

- Clause 6: Reference jack construction and measurement – the basics of the de-embedding test method

NOTE 3 Clause 6 describes the preparation and measurements of the reference plugs and jacks as a basis of the de-embedding test method.

The test methods provided here are:

- insertion loss, test 26a;
- return loss, test 26b;
- near-end crosstalk (NEXT), test 26c;
- far-end crosstalk (FEXT), test 26d;
- transfer impedance (Z_T), test 26e;
- transverse conversion loss (TCL), test 26f;
- transverse conversion transfer loss (TCTL), test 26g.

For the coupling attenuation, see EN 50289-1-14.

CONNECTORS FOR ELECTRONIC EQUIPMENT – TESTS AND MEASUREMENTS –

Part 26-100: Measurement setup, test and reference arrangements and measurements for connectors according to IEC 60603-7 – Tests 26a to 26g

1 Scope

This part of IEC 60512 specifies the test and measurements and the related measurement setup and reference arrangements for interoperability and backward compatibility tests for the development and qualification of 8-way, free and fixed connectors for data transmission.

2 Normative reference

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60169-15, *Radio-frequency connectors – Part 15: R.F. coaxial connectors with inner diameter of outer conductor 4.13 mm (0.163 in) with screw coupling – Characteristic impedance 50 ohms (Type SMA)*

IEC 60512-1, *Connectors for electronic equipment – Tests and measurements – Part 1: General*

IEC 60512-1-100, *Connectors for electronic equipment – Tests and measurements – Part 1-100: General – Applicable publications*

IEC 60603-7, *Connectors for frequencies below 3 MHz for use with printed boards – Part 7: Detail specification for connectors, 8-way, including fixed and free connectors with common mating features, with assessed quality*

IEC 60603-7-2, *Connectors for electronic equipment – Part 7-2: Detail specification for 8-way, unshielded, free and fixed connectors, for data transmissions with frequencies up to 100 MHz*

IEC 60603-7-3, *Connectors for electronic equipment – Part 7-3: Detail specification for 8-way, shielded, free and fixed connectors, for data transmissions with frequencies up to 100 MHz*

IEC 60603-7-4:2005, *Connectors for electronic equipment – Part: 7-4: Detail specification for 8-way, unshielded, free and fixed connectors, for data transmissions with frequencies up to 250 MHz*

IEC 60603-7-5:2007, *Connectors for electronic equipment – Part: 7-5: Detail specification for 8-way, shielded, free and fixed connectors, for data transmissions with frequencies up to 250 MHz*

IEC 61156 (all parts), *Multicore and symmetrical pair/quad cables for digital communications*

IEC 61169-16, *Radio-frequency connectors – Part 16: RF coaxial connectors with inner diameter of outer conductor 7 mm (0,276 in) with screw coupling – Characteristic impedance 50 ohms (75 ohms) (Type N)*

ISO 11801:2002, *Information technology – Generic cabling for customer premises*

ITU-T Recommendation G.117, *Transmission aspects of unbalance about earth*

ITU-T Recommendation O.9, *Measuring arrangements to assess the degree of unbalance about earth*

EN 50289-1-14, *Communication cables – Specification for test methods – Part 1-14: Electrical test methods – Coupling attenuation or screening attenuation of connecting hardware*

3 General requirements for measurement setup

3.1 Test instrumentation

These electrical test procedures require the use of a vector network analyser. The analyser shall have be capable of full 2-port calibrations. The analyser shall cover the frequency range of 1 MHz to 1 GHz at least.

At least two test baluns are required in order to perform measurements with balanced symmetrical signals. The requirements for the baluns are given in 3.4.

Reference loads and cables are needed for the calibration of the set-up. Requirements for the reference loads and cables are given in 3.5.1 and 3.5.2 respectively.

Termination loads are needed for termination of pairs, used and unused, which are not terminated by the test baluns. Requirements for the termination loads are given in 3.9.

An absorbing clamp and ferrite absorbers are needed for the coupling attenuation measurements. The requirements for these items are given in EN 50289-1-14.

3.2 Coaxial cables and test leads for network analysers

Coaxial cable assemblies between network analyser and baluns should be as short as possible. (It is recommended that they do not exceed 60 cm each.)

The baluns shall be electrically bonded to a common ground plane. For crosstalk measurements, a test fixture may be used, in order to reduce residual crosstalk (see 3.9 and Annex A).

Balanced test leads and associated connecting hardware to connect between the test equipment and the connector under test shall be taken from components that meet or exceed the requirements for the relevant class of balanced cabling performance according to ISO/IEC 11801. Balanced test leads shall be limited to a maximum of 7 cm between each balun and the reference plane of the connector under test. Pairs shall remain twisted from the baluns to where connections are made. The impedance of the test leads from the DUT (Device Under Test) to the baluns shall be managed, as far as possible, for both differential and common modes. This can be done by mounting the test leads in a pyramid, channel, or other device.

3.3 Measurement precautions

To assure a high degree of reliability for transmission measurements, the following precautions are required.

- a) Consistent and stable balun and resistor loads shall be used for each pair throughout the test sequence.